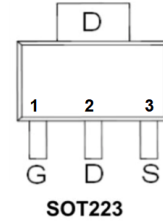


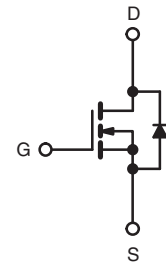
**DESCRIPTION**

The SOT-223 package is designed for surface-mounting using vapor phase, infrared, or wave soldering techniques. Its unique package design allows for easy automatic pick-and-place as with other SOT or SOIC packages but has the added advantage of improved thermal performance due to an enlarged tab for heatsinking. Power dissipation of greater than 1.25 W is possible in a typical surface mount application.



**FEATURES**

- $V_{DS}(V) = 100V$
- $R_{DS(ON)} < 54m\Omega (V_{GS} = 5V)$
- $R_{DS(ON)} < 76m\Omega (V_{GS} = 4V)$
- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- Logic-level gate drive
- $R_{DS(on)}$  specified at  $V_{GS} = 4 V$  and  $5 V$
- Fast switching
- Material categorization: for definitions of compliance



N-Channel MOSFET

**ABSOLUTE MAXIMUM RATINGS** ( $T_C = 25\text{ }^\circ\text{C}$ , unless otherwise noted)

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	$V_{DS}$	100	V
Gate-Source Voltage	$V_{GS}$	$\pm 10$	
Continuous Drain Current	$I_D$	$T_C = 25\text{ }^\circ\text{C}$	1.5
		$T_C = 100\text{ }^\circ\text{C}$	0.93
Pulsed Drain Current <sup>a</sup>	$I_{DM}$	12	A
Linear Derating Factor		0.025	W/ $^\circ\text{C}$
Linear Derating Factor (PCB Mount) <sup>e</sup>		0.017	
Single Pulse Avalanche Energy <sup>b</sup>	$E_{AS}$	50	mJ
Repetitive Avalanche Current <sup>a</sup>	$I_{AR}$	1.5	A
Repetitive Avalanche Energy <sup>a</sup>	$E_{AR}$	0.31	mJ
Maximum Power Dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	3.1
Maximum Power Dissipation (PCB Mount) <sup>e</sup>		$T_A = 25\text{ }^\circ\text{C}$	2.0
Peak Diode Recovery dV/dt <sup>c</sup>	dV/dt	5.5	V/ns
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	-55 to +150	$^\circ\text{C}$
Soldering Recommendations (Peak Temperature) <sup>d</sup>	for 10 s	300	

**Notes**

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- $V_{DD} = 25 V$ , starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $L = 25\text{ mH}$ ,  $R_g = 25\text{ }\Omega$ ,  $I_{AS} = 1.5\text{ A}$  (see fig. 12).
- $I_{SD} \leq 5.6\text{ A}$ ,  $di/dt \leq 75\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 150\text{ }^\circ\text{C}$ .
- 1.6 mm from case.
- When mounted on 1" square PCB (FR-4 or G-10 material).

THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	R <sub>thJA</sub>	-	60	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	40	

**Note**

a. When mounted on 1" square PCB (FR-4 or G-10 material).

SPECIFICATIONS (T <sub>J</sub> = 25 °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
<b>Static</b>							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA		100	-	-	V
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.12	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA		1.0	-	2.0	V
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>GS</sub> = ± 10 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V		-	-	25	μA
		V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	-	250	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 5.0 V	I <sub>D</sub> = 0.90 A <sup>b</sup>			54	mΩ
		V <sub>GS</sub> = 4.0 V	I <sub>D</sub> = 0.75 A			76	
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 25 V, I <sub>D</sub> = 0.90 A		0.57	-	-	S
<b>Dynamic</b>							
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 25 V, f = 1.0 MHz, see fig. 5		-	250	-	pF
Output Capacitance	C <sub>oss</sub>			-	80	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	15	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>GS</sub> = 5.0 V	I <sub>D</sub> = 5.6 A, V <sub>DS</sub> = 80 V, see fig. 6 and 13 <sup>b</sup>	-	-	6.1	nC
Gate-Source Charge	Q <sub>gs</sub>			-	-	2.6	
Gate-Drain Charge	Q <sub>gd</sub>			-	-	3.3	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 5.6 A, R <sub>g</sub> = 12 Ω, R <sub>D</sub> = 8.4 Ω		-	9.3	-	ns
Rise Time	t <sub>r</sub>			-	47	-	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	16	-	
Fall Time	t <sub>f</sub>			-	18	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	nH
Internal Source Inductance	L <sub>S</sub>			-	6.0	-	
<b>Drain-Source Body Diode Characteristics</b>							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	1.5	A
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-	-	12	
Body Diode Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 1.5 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = 5.6 A, dI/dt = 100 A/μs <sup>b</sup>		-	110	130	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	0.50	0.65	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> and L <sub>D</sub> )					

**Notes**

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width ≤ 300 μs; duty cycle ≤ 2 %.

**TYPICAL CHARACTERISTICS** (25 °C, unless otherwise noted)

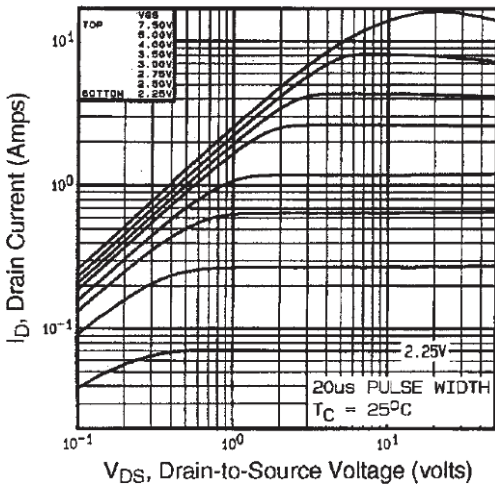


Fig. 1 - Typical Output Characteristics

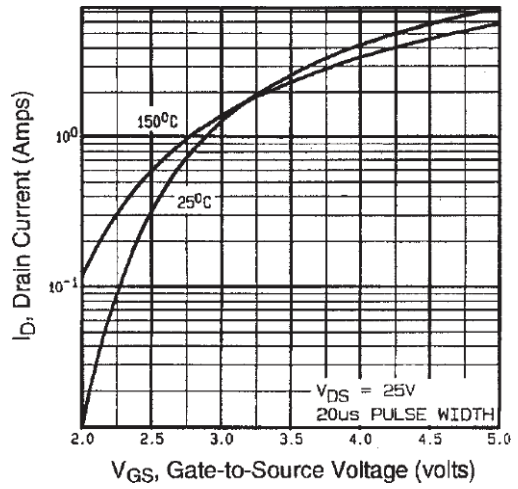


Fig. 3 - Typical Transfer Characteristics

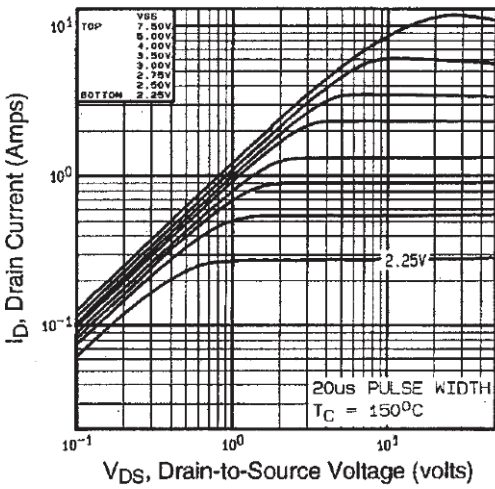


Fig. 2 - Typical Output Characteristics

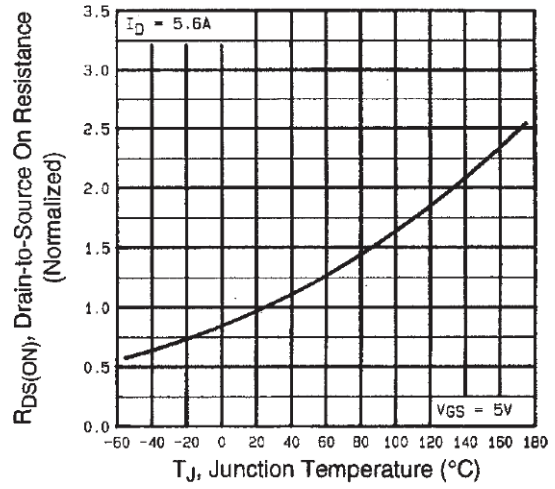


Fig. 4 - Normalized On-Resistance vs. Temperature

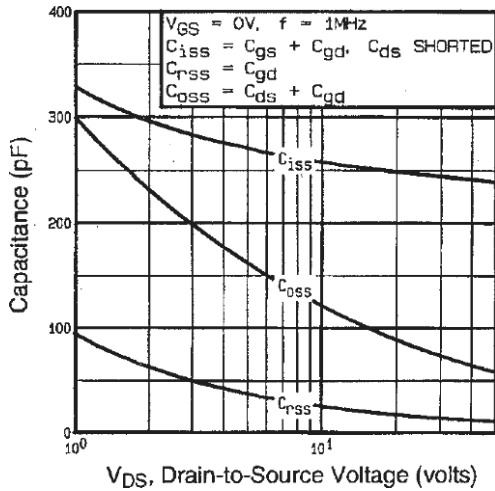


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

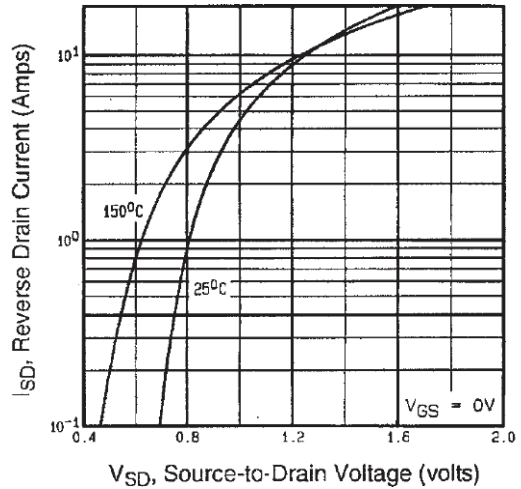


Fig. 7 - Typical Source-Drain Diode Forward Voltage

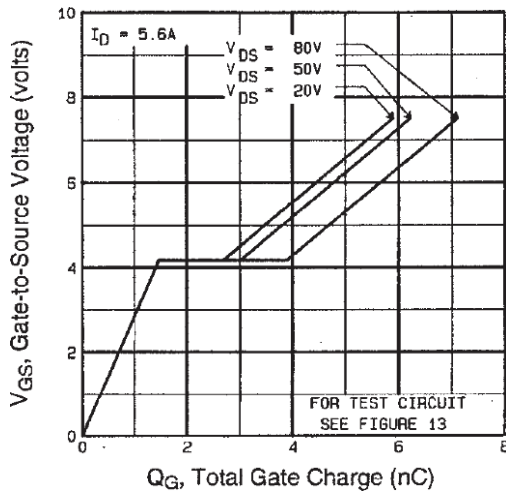


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

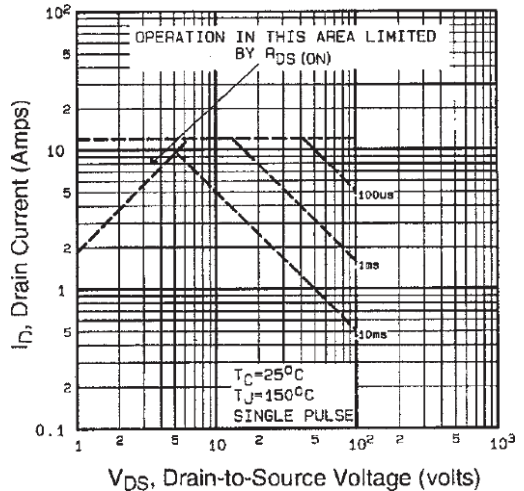


Fig. 8 - Maximum Safe Operating Area

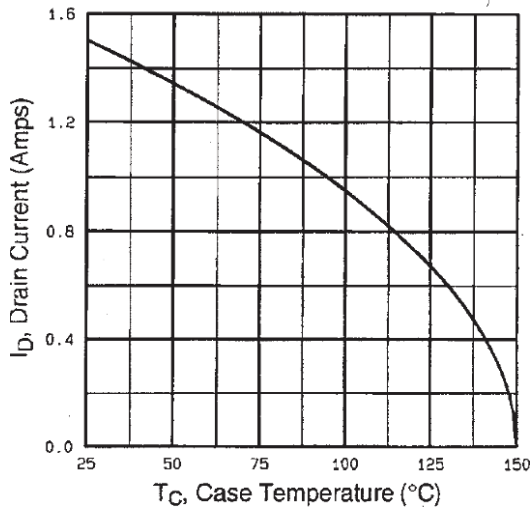


Fig. 9 - Maximum Drain Current vs. Case Temperature

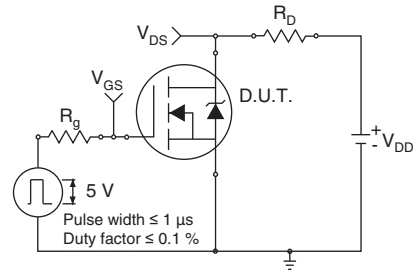


Fig. 10a - Switching Time Test Circuit

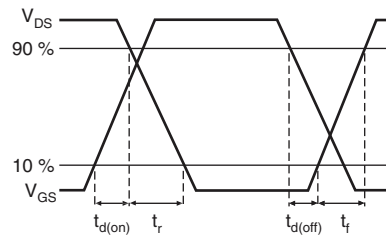


Fig. 10b - Switching Time Waveforms

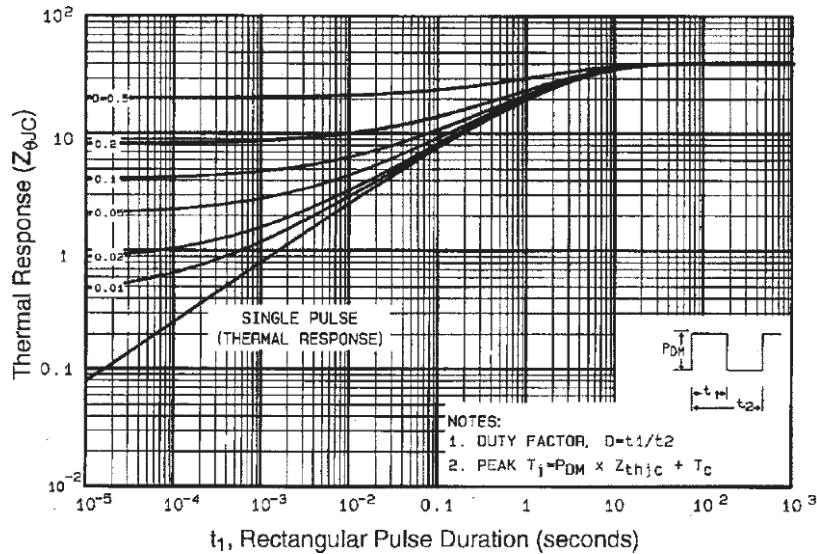


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

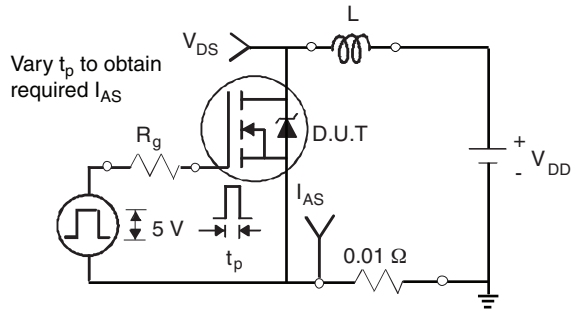


Fig. 12a - Unclamped Inductive Test Circuit

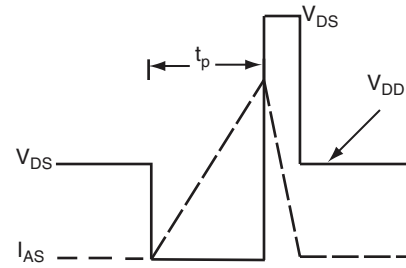


Fig. 12b - Unclamped Inductive Waveforms

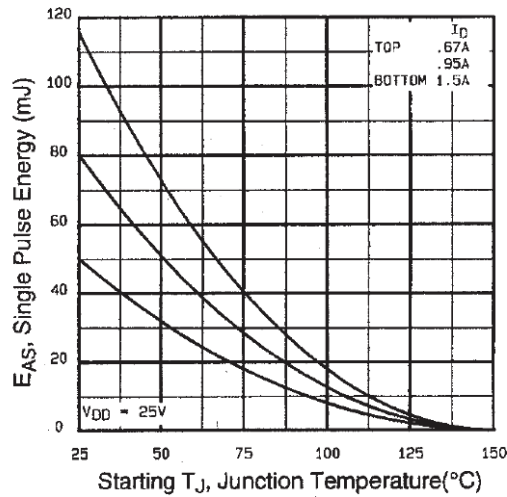


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

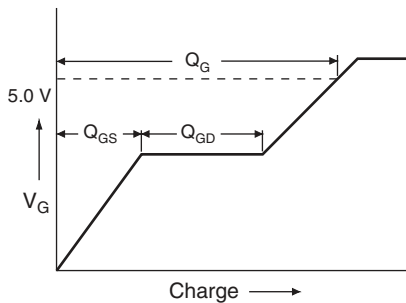


Fig. 13a - Basic Gate Charge Waveform

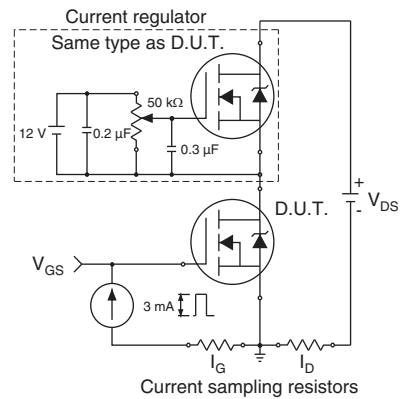
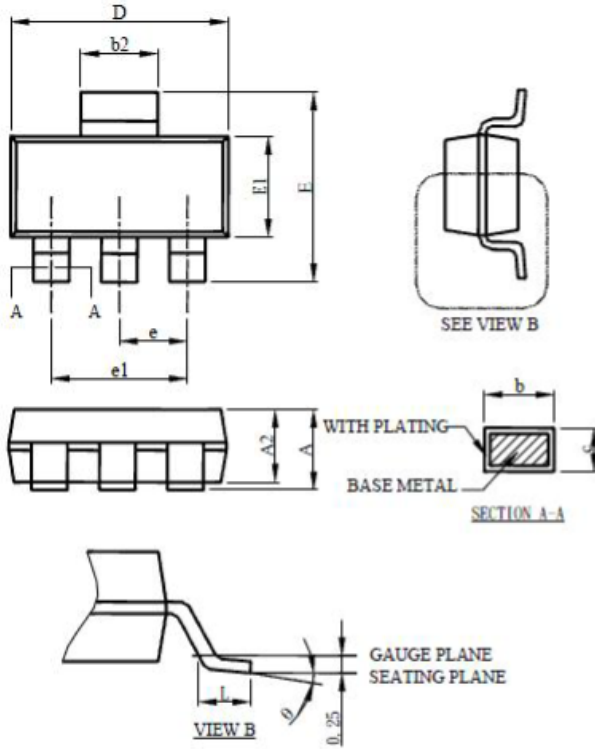


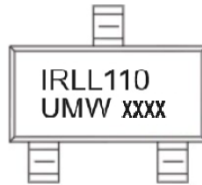
Fig. 13b - Gate Charge Test Circuit

PACKAGE OUTLINE DIMENSIONS



SYMBOL	SOT-223	
	MILLIMETERS	
	MIN.	MAX.
A		1.80
A1	0.02	0.10
A2	1.55	1.65
b	0.68	0.84
b <sub>2</sub>	2.90	3.10
c	0.23	0.33
D	6.30	6.70
E	6.70	7.30
E <sub>1</sub>	3.30	3.70
e	2.30 BSC	
e <sub>1</sub>	4.60 BSC	
L	0.90	
θ	0°	8°

### Marking



### Ordering information

Order code	Package	Baseqty	Deliverymode
UMW IRLL110TR	SOT-223	2500	Tape and reel



单击下面可查看定价，库存，交付和生命周期等信息

[>>UMW\(友台半导体\)](#)